

Application/Control No.	Applicant(s)/Pate Reexamination	ent under
10/579,194	LEE ET AL.	
Examiner	Art Unit	
Krichnen C. Menen	1707	

	SEAR	CHED	
Class	Subclass	Date	Examiner

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARCH		)
	DATE	EXMR
Inventor search; 210/650,652,321.69,500.23, 490	11/6/2008	KM